

#### **Description**

TheVSM100N06uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. This device is suitable for use in PWM, load switching and general purpose applications.

#### **General Features**

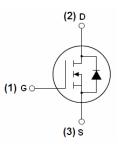
•  $V_{DS} = 60V, I_D = 100A$  $R_{DS(ON)} < 5.5 \text{ m}\Omega @ V_{GS} = 10V$  (Typ:4.8m $\Omega$ )

- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Special designed for convertors and power controls
- Good stability and uniformity with high E<sub>AS</sub>
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

#### **Application**

- Power switching application
- Hard switched and High frequency circuits
- Uninterruptible power supply





Schematic Diagram

#### **Package Marking and Ordering Information**

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
VSM100N06-TC	VSM100N06	TO-220C	-	-	-

#### Absolute Maximum Ratings (T<sub>A</sub>=25 ℃unless otherwise noted)

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V <sub>DS</sub>	60	V	
Gate-Source Voltage	Vgs	±20	V	
Drain Current-Continuous	I <sub>D</sub>	100	А	
Drain Current-Continuous(T <sub>C</sub> =100°C)	I <sub>D</sub> (100℃)	70	Α	
Pulsed Drain Current	I <sub>DM</sub>	320	Α	
Maximum Power Dissipation	P <sub>D</sub>	170	W	
Derating factor		1.13	W/℃	
Single pulse avalanche energy (Note 5)	E <sub>AS</sub>	812	mJ	
Operating Junction and Storage Temperature Range	$T_{J}$ , $T_{STG}$	-55 To 175	$^{\circ}$ C	



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#### **Thermal Characteristic**

Thermal Resistance, Junction-to-Case (Note 2)	R <sub>eJC</sub>	0.88	°C/W	
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## Electrical Characteristics (T<sub>A</sub>=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics			•			
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =250µA	60	-	-	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =60V,V <sub>GS</sub> =0V	-	-	1	μA
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V,V <sub>DS</sub> =0V	-	-	±100	nA
On Characteristics (Note 3)						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS},I_{D}=250\mu A$	2	2.85	4	V
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =20A	-	4.8	5.5	mΩ
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> =5V,I <sub>D</sub> =20A	-	50	-	S
Dynamic Characteristics (Note4)						
Input Capacitance	C <sub>lss</sub>	V <sub>DS</sub> =25V,V <sub>GS</sub> =0V,	-	4900	-	PF
Output Capacitance	C <sub>oss</sub>		-	380	-	PF
Reverse Transfer Capacitance	C <sub>rss</sub>	F=1.0MHz	-	290	-	PF
Switching Characteristics (Note 4)			•			
Turn-on Delay Time	t <sub>d(on)</sub>		-	17	-	nS
Turn-on Rise Time	t <sub>r</sub>	VDD=35V,RL=15Ω	-	11	-	nS
Turn-Off Delay Time	t <sub>d(off)</sub>	RG=2.5Ω,VGS=10V	-	55	-	nS
Turn-Off Fall Time	t <sub>f</sub>		-	15	-	nS
Total Gate Charge	Qg	V 20VI 00A	-	100	-	nC
Gate-Source Charge	Q <sub>gs</sub>	V <sub>DS</sub> =30V,I <sub>D</sub> =20A,	-	21	-	nC
Gate-Drain Charge	$Q_{gd}$	V <sub>GS</sub> =10V	-	30	-	nC
Drain-Source Diode Characteristics			•			
Diode Forward Voltage (Note 3)	$V_{SD}$	V <sub>GS</sub> =0V,I <sub>S</sub> =20A	-	-	1.2	V
Diode Forward Current (Note 2)	Is		-	-	100	Α
Reverse Recovery Time	t <sub>rr</sub>	Tj=25℃,I <sub>F</sub> =100A	-		37	nS
Reverse Recovery Charge	Qrr	di/dt=100A/µs <sup>(Note3)</sup>	-		58	nC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

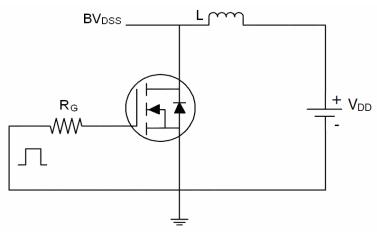
### Notes:

- $\textbf{1.} \ \textbf{Repetitive Rating: Pulse width limited by maximum junction temperature.}$
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- 3. Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2%.
- 4. Guaranteed by design, not subject to production
- **5.** EAS condition: Tj=25  $^{\circ}\text{C}$  ,VDD=35V,VG=10V,L=0.5mH,Rg=25 $\Omega$

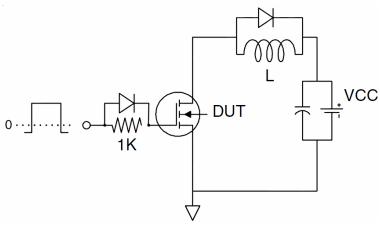


# **Test Circuit**

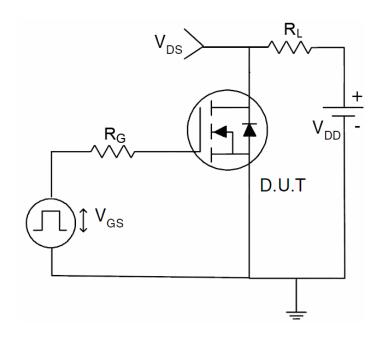
## 1) E<sub>AS</sub> Test Circuits



## 2) Gate Charge Test Circuit

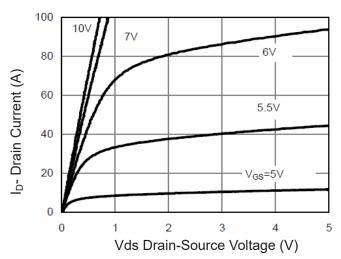


## 3) Switch Time Test Circuit

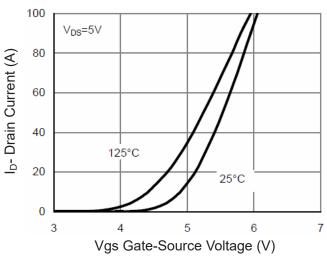




### **Typical Electrical and Thermal Characteristics (Curves**



**Figure 1 Output Characteristics** 



**Figure 2 Transfer Characteristics** 

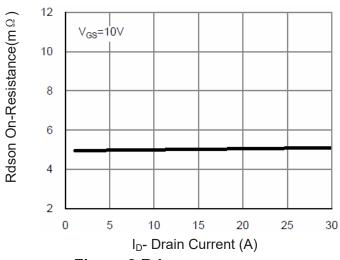


Figure 3 Rdson- Drain Current

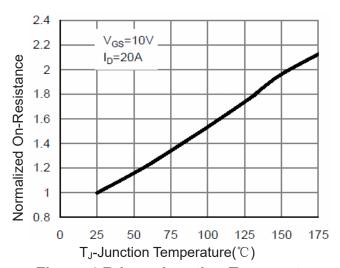


Figure 4 Rdson-Junction Temperature

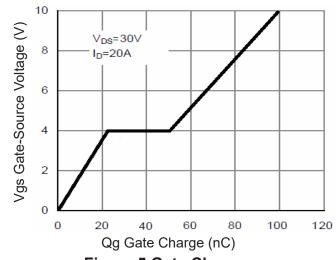


Figure 5 Gate Charge

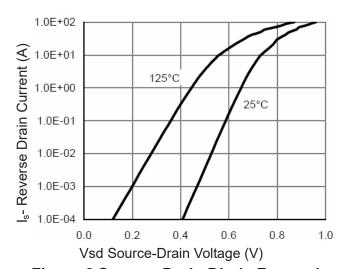


Figure 6 Source- Drain Diode Forward



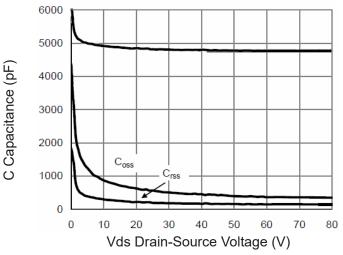
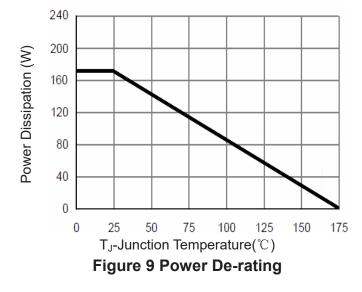


Figure 7 Capacitance vs Vds



1000.0 10μs 100.0 100μs limited 10.0 1ms DC 10ms 1.0 T<sub>J(Max)</sub>=175°C 0.1 T<sub>C</sub>=25°C 0.0 10 Vds Drain-Source Voltage (V)

Figure 8 Safe Operation Area

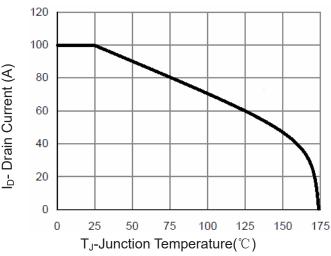
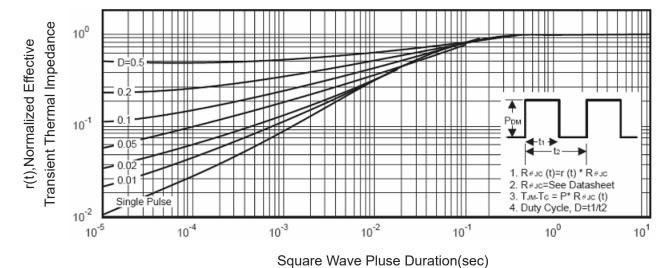


Figure 10 I<sub>D</sub> Current De-rating



**Figure 11 Normalized Maximum Transient Thermal Impedance**